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<input type="checkbox"/>	L4	L2 and porous and anodiz\$6	102
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<input type="checkbox"/>	L2	438/404-412,424-426.ccls.	2956
		<i>DB=PGPB,USPT,USOC,EPAB,JPAB,DWPI,TDBD; PLUR=YES; OP=OR</i>	
<input type="checkbox"/>	L1	porous and anodiz\$6 and ((dielectric with isolation) or SOI) and (via\$1 or trench\$2)	339

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<input type="text"/>	in All Fields	
AND <input type="text"/>	in All Fields	
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**OPTION 2**

Enter keywords, phrases, or a Boolean expression

porous <and> isolation <and> (anodize <or>  
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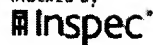
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## » Key

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IEEE CNF	IEEE Conference Proceeding
IEE CNF	IEE Conference Proceeding
IEEE STD	IEEE Standard

## Select Article Information

- ☐ 1. Effective crosstalk isolation through p<sup>+</sup> Si substrates with semi-insulating porous Si  
 Han-Su Kim; Jenkins, K.A.; Ya-Hong Xie;  
 Electron Device Letters, IEEE  
 Volume 23, Issue 3, March 2002 Page(s):160 - 162  
 Digital Object Identifier 10.1109/55.988824  
[AbstractPlus](#) | [References](#) | Full Text: [PDF](#)(201 KB) IEEE JNL
- ☐ 2. FIPOS (Full Isolation by Porous Oxidized Silicon) technology and its application to LSI's  
 Imai, K.; Unno, H.;  
 Electron Devices, IEEE Transactions on  
 Volume 31, Issue 3, Mar 1984 Page(s):297 - 302  
[AbstractPlus](#) | Full Text: [PDF](#)(752 KB) IEEE JNL
- ☐ 3. The "ISLANDS" method—A manufacturable porous silicon SOI technology  
 Zorinsky, E.J.; Spratt, D.B.; Virkus, R.L.;  
 1986 International Electron Devices Meeting  
 Volume 32, 1986 Page(s):431 - 434  
[AbstractPlus](#) | Full Text: [PDF](#)(688 KB) IEEE CNF
- ☐ 4. Fabrication of a micro-biochemical reactor with thick thermal isolation layer and integrated in the micro-well  
 Hoon-Sung Choi; Chang-Taeg Seo; Young-Min Kim; Jang-Kyoo Shin; Pyung Choi; Jong-Hyun Lee  
 Microprocesses and Nanotechnology Conference, 2003. Digest of Papers. 2003 International  
 29-31 Oct. 2003 Page(s):326 - 327  
[AbstractPlus](#) | Full Text: [PDF](#)(256 KB) IEEE CNF
- ☐ 5. An LED for silicon-based integrated optoelectronics  
 Tsybeskov, L.; Hirschman, K.D.; Duttagupta, S.P.; Fauchet, P.M.;  
 Device Research Conference, 1996. Digest. 54th Annual  
 24-26 June 1996 Page(s):150 - 151  
 Digital Object Identifier 10.1109/DRC.1996.546416  
[AbstractPlus](#) | Full Text: [PDF](#)(148 KB) IEEE CNF

